

## ADC0811 8-Bit Serial I/O A/D Converter With 11-Channel Multiplexer

### General Description

The ADC0811 is an 8-Bit successive approximation A/D converter with simultaneous serial I/O. The serial input controls an analog multiplexer which selects from 11 input channels or an internal half scale test voltage.

An input sample-and-hold is implemented by a capacitive reference ladder and sampled data comparator. This allows the input signal to vary during the conversion cycle.

Separate serial I/O and conversion clock inputs are provided to facilitate the interface to various microprocessors.

### Features

- Separate asynchronous converter clock and serial data I/O clock.
- 11-Channel multiplexer with 4-Bit serial address logic.
- Built-in sample and hold function.

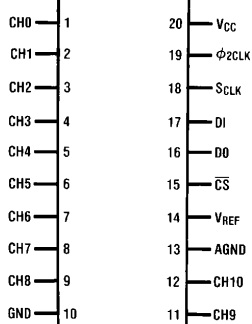
- Ratiometric or absolute voltage referencing.
- No zero or full-scale adjust required.
- Internally addressable test voltage.
- 0V to 5V input range with single 5V power supply.
- TTL/MOS input/output compatible.
- 0.3" standard width 20-pin dip or 20-pin molded chip carrier

### Key Specifications

- |                          |                                       |
|--------------------------|---------------------------------------|
| ■ Resolution             | 8-Bits                                |
| ■ Total unadjusted error | $\pm \frac{1}{2}$ LSB and $\pm 1$ LSB |
| ■ Single supply          | 5V <sub>DC</sub>                      |
| ■ Low Power              | 15 mW                                 |
| ■ Conversion Time        | 32 $\mu$ S                            |

### Connection Diagrams

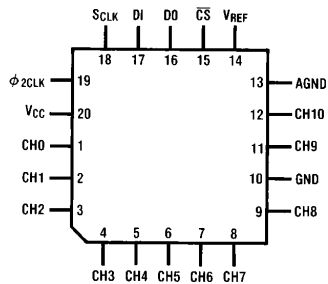
#### Dual-In-Line Package



Top View

TL/H/5587-1

#### Molded Chip Carrier (PCC) Package

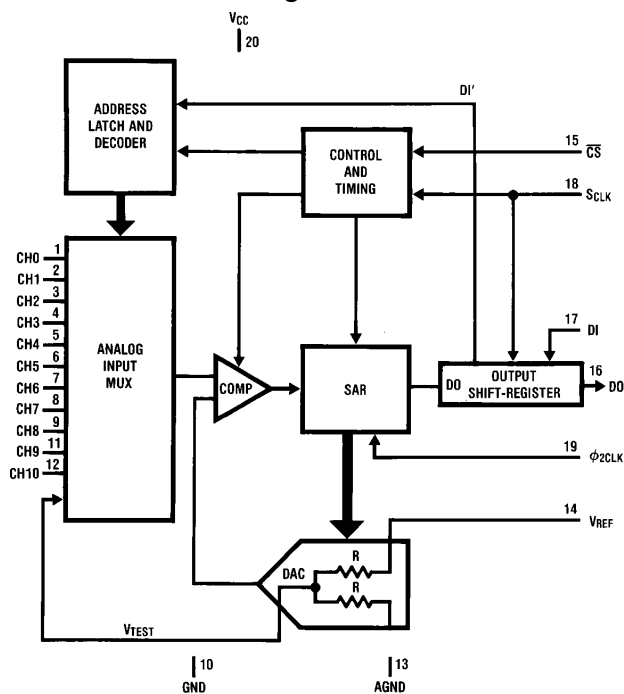


Top View

TL/H/5587-2

Order Number ADC0811J,N,V  
See NS Packages J20A, N20A, V20A  
Use Ordering Information

### Functional Diagram



TL/H/5587-3

## Absolute Maximum Ratings (Notes 1 & 2)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Supply Voltage ( $V_{CC}$ )	6.5V
Voltage	
Inputs and Outputs	$-0.3V$ to $V_{CC} + 0.3V$
Input Current Per Pin (Note 3)	$\pm 5mA$
Total Package Input Current (Note 3)	$\pm 20mA$
Storage Temperature	$-65^{\circ}C$ to $+150^{\circ}C$
Package Dissipation at $T_A = 25^{\circ}C$	875 mW

Lead Temp. (Soldering, 10 seconds)	
Dual-In-Line Package (plastic)	260°C
Dual-In-Line Package (ceramic)	300°C
Molded Chip Carrier Package	
Vapor Phase (60 seconds)	215°C
Infrared (15 seconds)	220°C
ESD Susceptibility (Note 11)	2000V

## Operating Ratings (Notes 1 & 2)

Supply Voltage ( $V_{CC}$ )	$4.5 V_{DC}$ to $6.0 V_{DC}$
Temperature Range	$T_{MIN} \leq T_A \leq T_{MAX}$
ADC0811BCN, ADC0811CCN	$0^{\circ}C \leq T_A \leq 70^{\circ}C$
ADC0811BCV	$-40^{\circ}C \leq T_A \leq 85^{\circ}C$
ADC0811CCJ, ADC0811CCV	$-40^{\circ}C \leq T_A \leq 85^{\circ}C$

## Electrical Characteristics

The following specifications apply for  $V_{CC} = 4.75V$  to  $5.25V$ ,  $V_{REF} = +4.6V$  to  $(V_{CC} + 0.1V)$ ,  $\phi_2 CLK = 2.097 MHz$  unless otherwise specified. **Boldface limits apply from  $T_{MIN}$  to  $T_{MAX}$** ; all other limits  $T_A = T_J = 25^{\circ}C$ .

Parameter	Conditions	ADC0811CCJ			ADC0811BCN, ADC0811BCV ADC0811CCN, ADC0811CCV			Units
		Typical (Note 6)	Tested Limit (Note 7)	Design Limit (Note 8)	Typical (Note 6)	Tested Limit (Note 7)	Design Limit (Note 8)	
<b>CONVERTER AND MULTIPLEXER CHARACTERISTICS</b>								
Maximum Total Unadjusted Error ADC0811BCN, ADC0811BCV ADC0811CCN, ADC0811CCV ADC0811CCJ	$V_{REF} = 5.00 V_{DC}$ (Note 4)		<b><math>\pm 1</math></b>			$\pm \frac{1}{2}$ $\pm 1$	$\pm \frac{1}{2}$ <b><math>\pm 1</math></b>	LSB LSB LSB
Minimum Reference Input Resistance		8		<b>5</b>	8		<b>5</b>	k $\Omega$
Maximum Reference Input Resistance		8	<b>11</b>		8	11	<b>11</b>	k $\Omega$
Maximum Analog Input Range	(Note 5)		<b><math>V_{CC} + 0.05</math></b>		$V_{CC} + 0.05$	<b><math>V_{CC} + 0.05</math></b>		V
Minimum Analog Input Range			<b><math>GND - 0.05</math></b>		$GND - 0.05$	<b><math>GND - 0.05</math></b>		V
On Channel Leakage Current ADC0811BCJ, CCJ, BCN, CCN, BCV, CCV	On Channel = 5V Off Channel = 0V		<b>1000</b>		400	<b>1000</b>		nA
ADC0811CJ, BJ			<b>1000</b>					nA
ADC0811BCJ, CCJ, BCN, CCN, BCV, CCV	On Channel = 0V Off Channel = 5V (Note 9)		<b>-1000</b>		-400	<b>-1000</b>		nA
ADC0811BJ, CJ			<b>-1000</b>					nA
Off Channel Leakage Current ADC0811BCJ, CCJ, BCN, CCN, BCV, CCV	On Channel = 5V Off Channel = 0V		<b>-1000</b>		-400	<b>1000</b>		nA
ADC0811CJ, BJ			<b>-1000</b>					nA
ADC0811BCJ, CCJ, BCN, CCN, BCV, CCV	On Channel = 0V Off Channel = 5V (Note 9)		<b>1000</b>		400	<b>1000</b>		nA
ADC0811BJ, CJ			<b>1000</b>					nA
Minimum $V_{TEST}$ Internal Test Voltage	$V_{REF} = V_{CC}$ , CH 11 Selected		<b>125</b>		125	<b>125</b>		(Note 10) Counts
Maximum $V_{TEST}$ Internal Test Voltage	$V_{REF} = V_{CC}$ , CH 11 Selected		<b>130</b>		130	<b>130</b>		(Note 10) Counts

## Electrical Characteristics

The following specifications apply for  $V_{CC} = 4.75V$  to  $5.25V$ ,  $V_{REF} = +4.6V$  to  $(V_{CC} + 0.1V)$ ,  $\phi_2 CLK = 2.097$  MHz unless otherwise specified. **Boldface limits apply from  $T_{MIN}$  to  $T_{MAX}$** ; all other limits  $T_A = T_J = 25^\circ C$ . (Continued)

Parameter	Conditions	ADC0811CCJ			ADC0811BCN, ADC0811BCV ADC0811CCN, ADC0811CCV			Units
		Typical (Note 6)	Tested Limit (Note 7)	Design Limit (Note 8)	Typical (Note 6)	Tested Limit (Note 7)	Design Limit (Note 8)	
<b>DIGITAL AND DC CHARACTERISTICS</b>								
$V_{IN(1)}$ , Logical "1" Input Voltage (Min)	$V_{CC} = 5.25V$		<b>2.0</b>			2.0	<b>2.0</b>	V
$V_{IN(0)}$ , Logical "0" Input Voltage (Max)	$V_{CC} = 4.75V$		<b>0.8</b>			0.8	<b>0.8</b>	V
$I_{IN(1)}$ , Logical "1" Input Current (Max)	$V_{IN} = 5.0V$	0.005	<b>2.5</b>		0.005	2.5	<b>2.5</b>	$\mu A$
$I_{IN(0)}$ , Logical "0" Input Current (Max)	$V_{IN} = 0V$	-0.005	<b>-2.5</b>		-0.005	2.5	<b>-2.5</b>	$\mu A$
$V_{OUT(1)}$ , Logical "1" Output Voltage (Min)	$V_{CC} = 4.75V$ $I_{OUT} = -360 \mu A$ $I_{OUT} = -10 \mu A$		<b>2.4</b>			2.4	<b>2.4</b>	V
			<b>4.5</b>			4.5	<b>4.5</b>	V
$V_{OUT(0)}$ , Logical "0" Output Voltage (Max)	$V_{CC} = 5.25V$ $I_{OUT} = 1.6 mA$		<b>0.4</b>			0.4	<b>0.4</b>	V
$I_{OUT}$ , TRI-STATE Output Current (Max)	$V_{OUT} = 0V$ $V_{OUT} = 5V$	-0.01	<b>-3</b>		-0.01	-3	<b>-3</b>	$\mu A$
		0.01	<b>3</b>		0.01	3	<b>3</b>	$\mu A$
$I_{SOURCE}$ , Output Source Current (Min)	$V_{OUT} = 0V$	-12	<b>-6.5</b>		-14	-6.5	<b>-6.5</b>	mA
$I_{SINK}$ , Output Sink Current (Min)	$V_{OUT} = V_{CC}$	18	<b>8.0</b>		16	8.0	<b>8.0</b>	mA
$I_{CC}$ , Supply Current (Max)	$\overline{CS} = 1$ , $V_{REF}$ Open	1	<b>2.5</b>		1	2.5	<b>2.5</b>	mA
$I_{REF}$ (Max)	$V_{REF} = 5V$	<b>0.7</b>	<b>1</b>		<b>0.7</b>	1	<b>1</b>	mA

## AC CHARACTERISTICS

Parameter	Conditions	Typical (Note 6)	Tested Limit (Note 7)	Design Limit (Note 8)	Units
$\phi_2 CLK$ , $\phi_2$ Clock Frequency	MIN	0.70		<b>1.0</b>	MHz
	MAX	3.0	2.0	<b>2.1</b>	
$S_{CLK}$ , Serial Data Clock Frequency	MIN			<b>5.0</b>	KHz
	MAX	700	525	<b>525</b>	
$T_C$ , Conversion Process Time	MIN	48		<b>48</b>	$\phi_2$ cycles
	MAX	64		<b>64</b>	
$t_{ACC}$ , Access Time Delay From $\overline{CS}$ Falling Edge to DO Data Valid	MIN			<b>1</b>	$\phi_2$ cycles
	MAX			<b>3</b>	
$t_{SET-UP}$ , Minimum Set-up Time of $\overline{CS}$ Falling Edge to $S_{CLK}$ Rising Edge				<b><math>4/\phi_2 CLK + \frac{1}{2 S_{CLK}}</math></b>	sec
$t_{H\overline{CS}}$ , $\overline{CS}$ Hold Time After the Falling Edge of $S_{CLK}$				<b>0</b>	ns
$t_{\overline{CS}}$ , Total $\overline{CS}$ Low Time	MIN			<b><math>t_{set-up} + 8/S_{CLK}</math></b>	sec
	MAX			<b><math>t_{\overline{CS}(min)} + 48/\phi_2 CLK</math></b>	sec
$t_{HDI}$ , Minimum DI Hold Time from $S_{CLK}$ Rising Edge		0		<b>0</b>	ns
$t_{HDO}$ , Minimum DO Hold Time from $S_{CLK}$ Falling Edge	$R_L = 30k$ , $C_L = 100 pF$			<b>10</b>	ns

## Electrical Characteristics

The following specifications apply for  $V_{CC} = 4.75V$  to  $5.25V$ ,  $V_{REF} = +4.6V$  to  $(V_{CC} + 0.1V)$ ,  $\phi_2 CLK = 2.097$  MHz unless otherwise specified. **Boldface limits apply from  $T_{MIN}$  to  $T_{MAX}$** ; all other limits  $T_A = T_J = 25^\circ C$ . (Continued)

Parameter	Conditions	Typical (Note 6)	Tested Limit (Note 7)	Design Limit (Note 8)	Units
<b>AC CHARACTERISTICS</b> (Continued)					
$t_{SDI}$ , Minimum DI Set-up Time to $S_{CLK}$ Rising Edge		200		<b>400</b>	ns
$t_{DDO}$ , Maximum Delay From $S_{CLK}$ Falling Edge to DO Data Valid	$R_L = 30k$ , $C_L = 100$ pF	180	400	<b>400</b>	ns
$t_{TRI}$ , Maximum DO Hold Time, ( $\overline{CS}$ Rising edge to DO TRI-STATE)	$R_L = 3k$ , $C_L = 100$ pF	90	150	<b>150</b>	ns
$t_{CA}$ , Analog Sampling Time	After Address Is Latched $\overline{CS} = Low$			<b><math>4/S_{CLK} + 1 \mu s</math></b>	sec
$t_{RDO}$ , Maximum DO Rise Time	$R_L = 30$ k $\Omega$ , “TRI-STATE” to “HIGH” State	75	150	<b>150</b>	ns
	$C_L = 100$ pf “LOW” to “HIGH” State	150	300	<b>300</b>	
$t_{FDO}$ , Maximum DO Fall Time	$R_L = 30$ k $\Omega$ , “TRI-STATE” to “LOW” State	75	150	<b>150</b>	ns
	$C_L = 100$ pf “HIGH” to “LOW” State	150	300	<b>300</b>	
$C_{IN}$ , Maximum Input Capacitance	Analog Inputs, AN0–AN10 and $V_{REF}$	11		<b>55</b>	pF
	All Others	5		<b>15</b>	

**Note 1:** Absolute Maximum Ratings indicate limits beyond which damage to the device may occur. DC and AC electrical specifications do not apply when operating the device beyond its specified operating conditions.

**Note 2:** All voltages are measured with respect to ground.

**Note 3:** Under over voltage conditions ( $V_{IN} < 0V$  and  $V_{IN} > V_{CC}$ ) the maximum input current at any one pin is  $\pm 5$  mA. If the voltage at more than one pin exceeds  $V_{CC} + .3V$  the total package current must be limited to 20 mA. For example the maximum number of pins that can be over driven at the maximum current level of  $\pm 5$  mA is four.

**Note 4:** Total unadjusted error includes offset, full-scale, linearity, multiplexer, and hold step errors.

**Note 5:** Two on-chip diodes are tied to each analog input, which will forward-conduct for analog input voltages one diode drop below ground or one diode drop greater than  $V_{CC}$  supply. Be careful during testing at low  $V_{CC}$  levels (4.5V), as high level analog inputs (5V) can cause this input diode to conduct, especially at elevated temperatures, and cause errors for analog inputs near full-scale. The spec allows 50 mV forward bias of either diode. This means that as long as the analog  $V_{IN}$  does not exceed the supply voltage by more than 50 mV, the output code will be correct. To achieve an absolute 0  $V_{DC}$  to 5  $V_{DC}$  input voltage range will therefore require a minimum supply voltage of 4.950  $V_{DC}$  over temperature variations, initial tolerance and loading.

**Note 6:** Typicals are at  $25^\circ C$  and represent most likely parametric norm.

**Note 7:** Guaranteed and 100% production tested under worst case condition.

**Note 8:** Guaranteed, but not 100% production tested. These limits are not used to calculate outgoing quality levels.

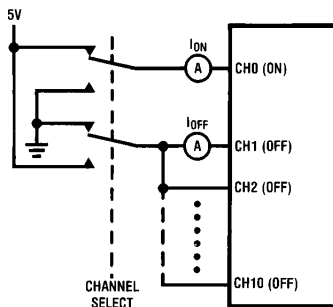
**Note 9:** Channel leakage current is measured after the channel selection.

**Note 10:** 1 count =  $V_{REF}/256$ .

**Note 11:** Human body model, 100 pF discharged through a 1.5 k $\Omega$  resistor.

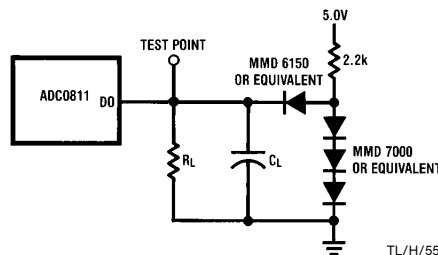
## Test Circuits

Leakage Current



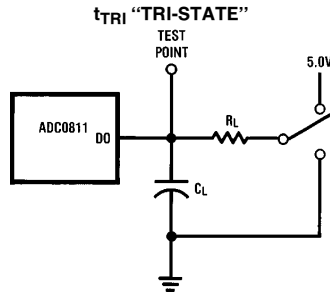
TL/H/5587-17

DO Except “TRI-STATE”



TL/H/5587-6

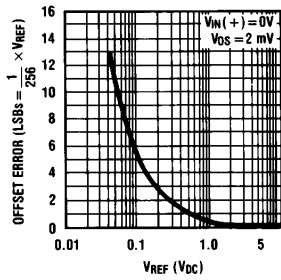
## Test Circuits (Continued)



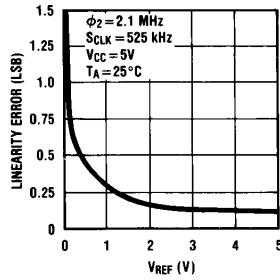
TL/H/5587-22

## Typical Performance Characteristics

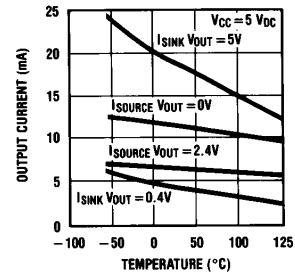
**Unadjusted Offset Error vs  $V_{REF}$  Voltage**



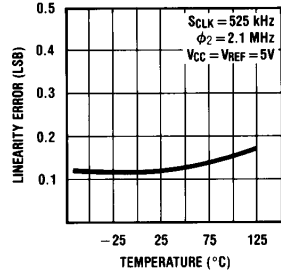
**Linearity Error vs  $V_{REF}$  Voltage**



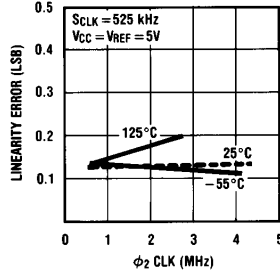
**Output Current vs Temperature**



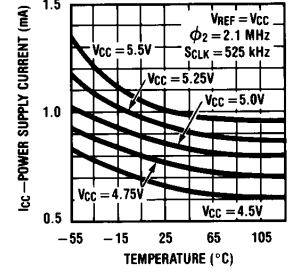
**Linearity vs Temperature**



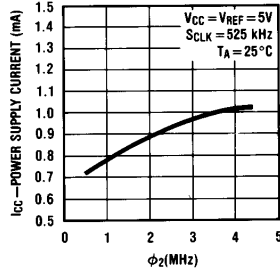
**Linearity vs  $\phi_2$  Clock Frequency**



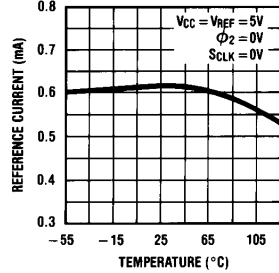
**Power Supply Current vs Temperature**



**Power Supply Current vs  $\phi_2$  Clock Frequency**



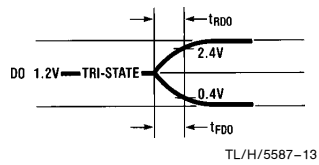
**Resistive Ladder Reference Current vs Temperature**



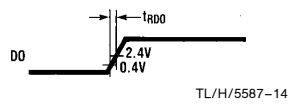
TL/H/5587-16

## Timing Diagrams

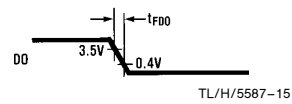
D0 "TRI-STATE" Rise & Fall Times



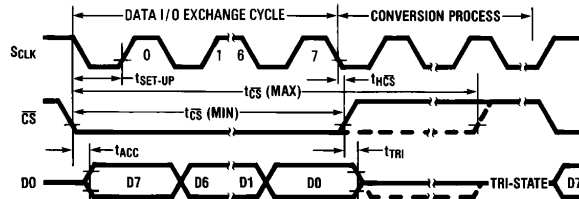
D0 Low to High State



D0 High to Low State

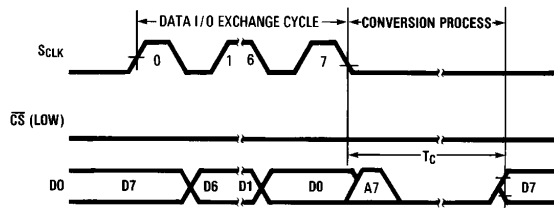


Timing with a continuous SCLK

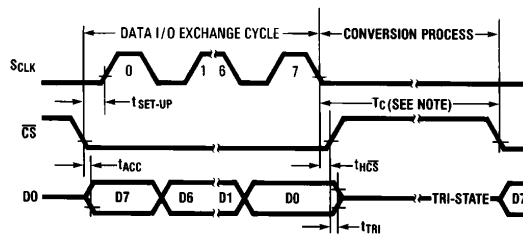


\*Strobing  $\overline{CS}$  High and Low will abort the present conversion and initiate a new serial I/O exchange.

Timing with a gated SCLK and  $\overline{CS}$  Continuously Low

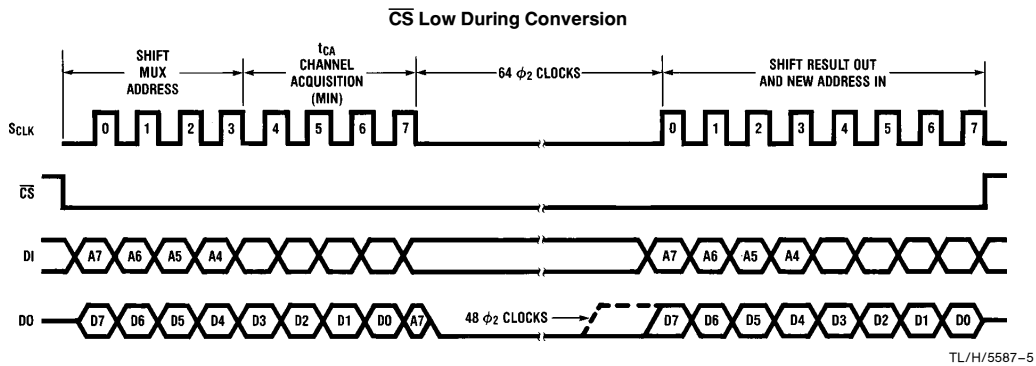
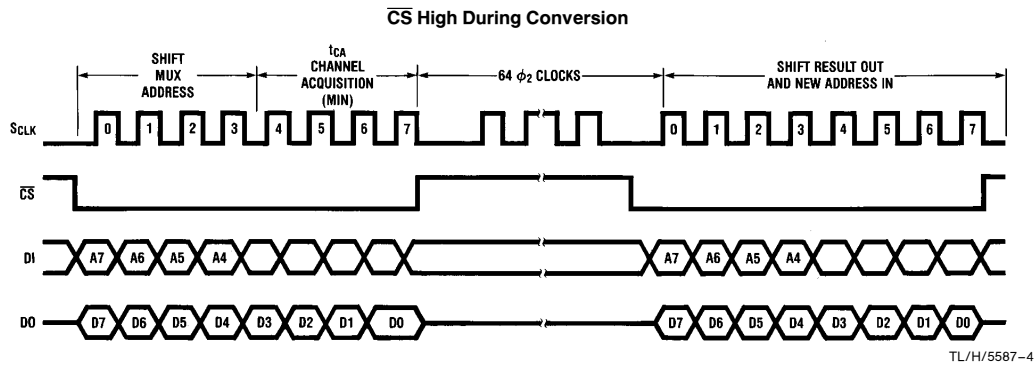


Using  $\overline{CS}$  To TRI-STATE D0



**Note:** Strobing  $\overline{CS}$  Low during this time interval will abort the conversion in process.

## Timing Diagrams (Continued)



**Note:** DO and DI lines share the 8-bit I/O shift register (see Functional Block Diagram). Since the MUX address bits are shifted in on  $S_{CLK}$  rising edges while  $S_{CLK}$  falling edges shift out conversion data on DO, the eighth falling edge of  $S_{CLK}$  will shift out the MSB MUX address bit (A7) on DO. Thus, if addressing channels CH8–CH10, a high DO will occur momentarily (one  $\phi_2$  clock period) until the 8-bit I/O shift register is cleared by the internal EOC signal.

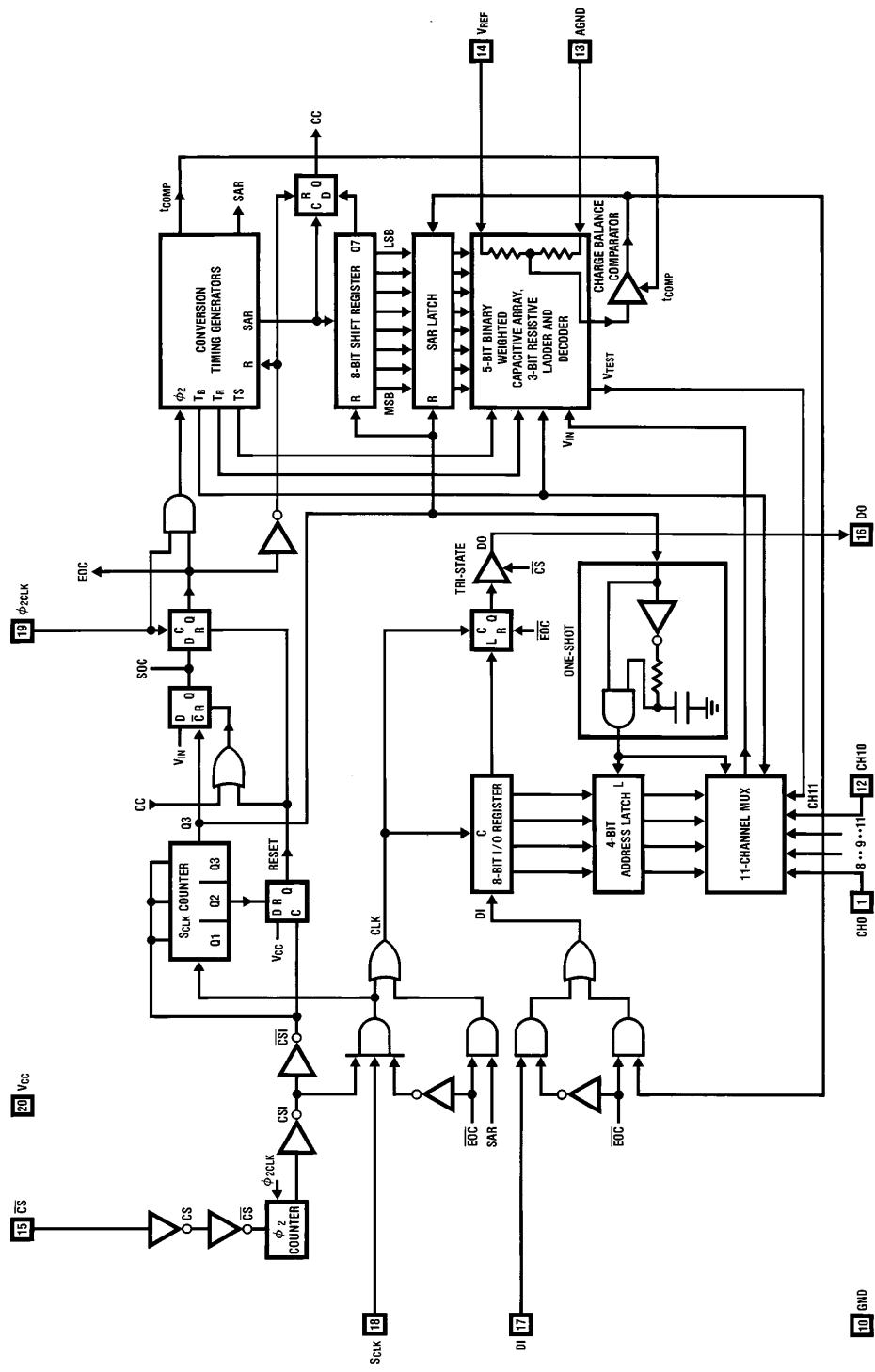
## Channel Addressing Table

TABLE I. ADC 0811 Channel Addressing

MUX ADDRESS								ANALOG CHANNEL SELECTED
A <sub>7</sub>	A <sub>6</sub>	A <sub>5</sub>	A <sub>4</sub>	A <sub>3</sub>	A <sub>2</sub>	A <sub>1</sub>	A <sub>0</sub>	
0	0	0	0	X	X	X	X	CH0
0	0	0	1	X	X	X	X	CH1
0	0	1	0	X	X	X	X	CH2
0	0	1	1	X	X	X	X	CH3
0	1	0	0	X	X	X	X	CH4
0	1	0	1	X	X	X	X	CH5
0	1	1	0	X	X	X	X	CH6
0	1	1	1	X	X	X	X	CH7
1	0	0	0	X	X	X	X	CH8
1	0	0	1	X	X	X	X	CH9
1	0	1	0	X	X	X	X	CH10
1	0	1	1	X	X	X	X	V <sub>TEST</sub>
1	1	X	X	X	X	X	X	LOGIC TEST MODE*

\* Analog channel inputs CH0 thru CH3 are logic outputs

# Functional Block Diagram



TL/H/5587-8

# Functional Description

## 1.0 DIGITAL INTERFACE

The ADC0811 uses five input/output pins to implement the serial interface. Taking chip select ( $\overline{CS}$ ) low enables the I/O data lines (DO and DI) and the serial clock input (S<sub>CLK</sub>). The result of the last conversion is transmitted by the A/D on the DO line, while simultaneously the DI line receives the address data that selects the mux channel for the next conversion. The mux address is shifted in on the rising edge of S<sub>CLK</sub> and the conversion data is shifted out on the falling edge. It takes eight S<sub>CLK</sub> cycles to complete the serial I/O. A second clock ( $\phi_2$ ) controls the SAR during the conversion process and must be continuously enabled.

### 1.1 CONTINUOUS S<sub>CLK</sub>

With a continuous S<sub>CLK</sub> input  $\overline{CS}$  must be used to synchronize the serial data exchange (see Figure 1). The ADC0811 recognizes a valid  $\overline{CS}$  one to three  $\phi_2$  clock periods after the actual falling edge of  $\overline{CS}$ . This is implemented to ensure noise immunity of the  $\overline{CS}$  signal. Any spikes on  $\overline{CS}$  less than one  $\phi_2$  clock period will be ignored.  $\overline{CS}$  must remain low during the complete I/O exchange which takes eight S<sub>CLK</sub> cycles. Although  $\overline{CS}$  is not immediately acknowledged for the purpose of starting a new conversion, the falling edge of  $\overline{CS}$  immediately enables DO to output the MSB (D7) of the previous conversion.

The first S<sub>CLK</sub> rising edge will be acknowledged after a set-up time ( $t_{set-up}$ ) has elapsed from the falling edge of  $\overline{CS}$ . This and the following seven S<sub>CLK</sub> rising edges will shift in the channel address for the analog multiplexer. Since there are 12 channels only four address bits are utilized. The first four S<sub>CLK</sub> cycles clock in the mux address, during the next four S<sub>CLK</sub> cycles the analog input is selected and sampled. During

this mux address/sample cycle, data from the last conversion is also clocked out on DO. Since D7 was clocked out on the falling edge of  $\overline{CS}$  only data bits D6–D0 remain to be received. The following seven falling edges of S<sub>CLK</sub> shift out this data on DO.

The 8th S<sub>CLK</sub> falling edge initiates the beginning of the A/D's actual conversion process which takes between 48 to 64  $\phi_2$  cycles ( $T_C$ ). During this time  $\overline{CS}$  can go high to TRI-STATE DO and disable the S<sub>CLK</sub> input or it can remain low. If  $\overline{CS}$  is held low a new I/O exchange will not start until the conversion sequence has been completed, however once the conversion ends serial I/O will immediately begin. Since there is an ambiguity in the conversion time ( $T_C$ ) synchronizing the data exchange is impossible. Therefore  $\overline{CS}$  should go high before the 48th  $\phi_2$  clock has elapsed and return low after the 64th  $\phi_2$  to synchronize serial communication.

A conversion or I/O operation can be aborted at any time by strobing  $\overline{CS}$ . If  $\overline{CS}$  is high or low less than one  $\phi_2$  clock it will be ignored by the A/D. If the  $\overline{CS}$  is strobed high or low between 1 to 3  $\phi_2$  clocks the A/D may or may not respond. Therefore  $\overline{CS}$  must be strobed high or low greater than 3  $\phi_2$  clocks to ensure recognition. If a conversion or I/O exchange is aborted while in process the consequent data output will be erroneous until a complete conversion sequence has been implemented.

### 1.2 DISCONTINUOUS S<sub>CLK</sub>

Another way to accomplish synchronous serial communication is to tie  $\overline{CS}$  low continuously and disable S<sub>CLK</sub> after its 8th falling edge (see Figure 2). S<sub>CLK</sub> must remain low for

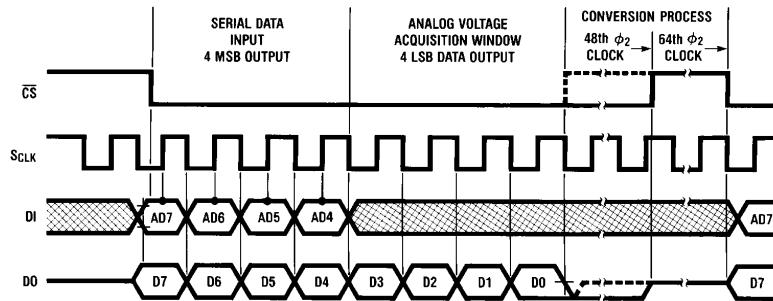


FIGURE 1

TL/H/5587-18

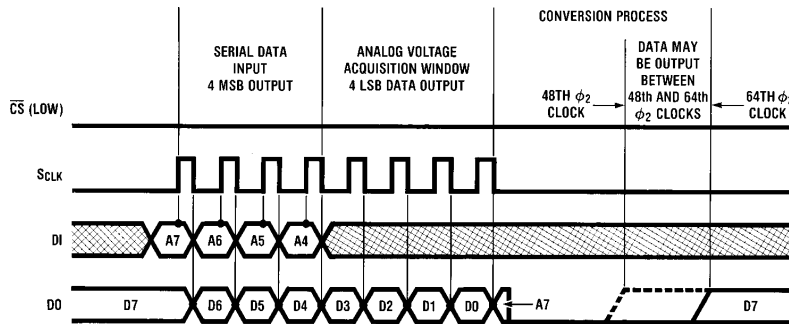


FIGURE 2

TL/H/5587-19

## Functional Description (Continued)

at least  $64 \phi_2$  clocks to insure that the A/D has completed its conversion. If  $S_{CLK}$  is enabled sooner, synchronizing to the data output on DO is not possible since an end of conversion signal from the A/D is not available and the actual conversion time is not known. With  $\overline{CS}$  low during the conversion time ( $64 \phi_2$  max) DO will go low after the eighth falling edge of  $S_{CLK}$  and remain low until the conversion is completed. Once the conversion is through DO will transmit the MSB. The rest of the data will be shifted out once  $S_{CLK}$  is enabled as discussed previously.

If  $\overline{CS}$  goes high during the conversion sequence DO is tri-stated, and the result is not affected so long as  $\overline{CS}$  remains high until the end of the conversion.

### 1.2 MULTIPLEXER ADDRESSING

The four bit mux address is shifted, MSB first, into DI. Input data corresponds to the channel selected as shown in table 1. Care should be taken not to send an address greater than or equal to twelve (11XX) as this puts the A/D in a digital testing mode. In this mode the analog inputs CH0 thru CH3 become digital outputs, for our use in production testing.

## 2.0 ANALOG INPUT

### 2.1 THE INPUT SAMPLE AND HOLD

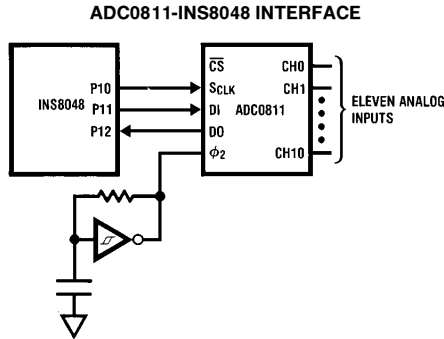
The ADC0811's sample/hold capacitor is implemented in its capacitive ladder structure. After the channel address is received, the ladder is switched to sample the proper analog input. This sampling mode is maintained for  $1 \mu\text{sec}$  after the

eighth  $S_{CLK}$  falling edge. The hold mode is initiated with the start of the conversion process. An acquisition window of  $4t_{S_{CLK}} + 1 \mu\text{sec}$  is therefore available to allow the ladder capacitance to settle to the analog input voltage. Any change in the analog voltage before or after the acquisition window will not effect the A/D conversion result.

In the most simple case, the ladder's acquisition time is determined by the  $R_{on}$  (3K) of the multiplexer switches and the total ladder capacitance (90pf). These values yield an acquisition time of about  $2 \mu\text{sec}$  for a full scale reading. Therefore the analog input must be stable for at least  $2 \mu\text{sec}$  before and  $1 \mu\text{sec}$  after the eighth  $S_{CLK}$  falling edge to ensure a proper conversion. External input source resistance and capacitance will lengthen the acquisition time and should be accounted for.

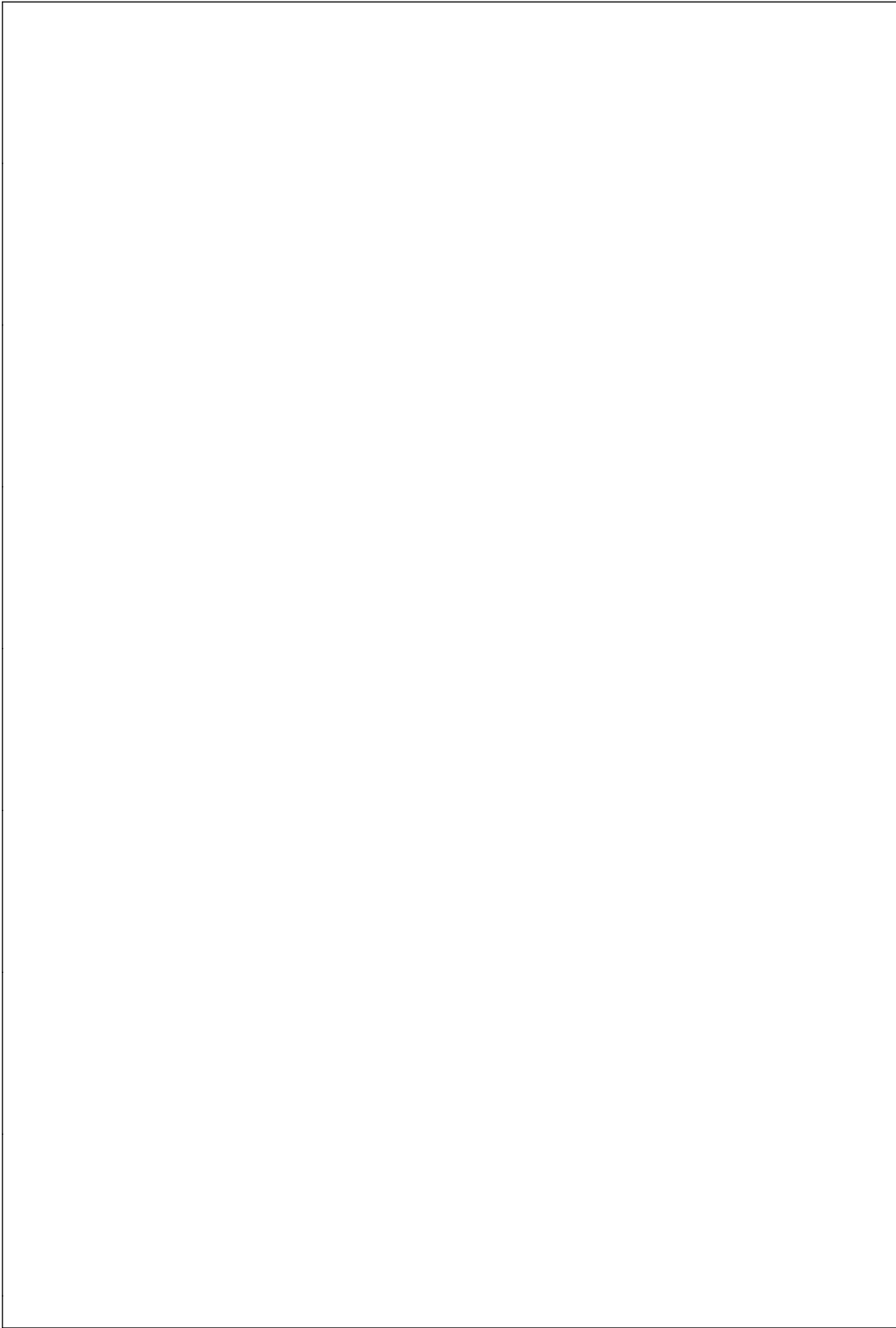
Other conventional sample and hold error specifications are included in the error and timing specs of the A/D. The hold step and gain error sample/hold specs are taken into account in the ADC0811's total unadjusted error, while the hold settling time is included in the A/D's max conversion time of  $64 \phi_2$  clock periods. The hold droop rate can be thought of as being zero since an unlimited amount of time can pass between a conversion and the reading of data. However, once the data is read it is lost and another conversion is started.

## Typical Applications

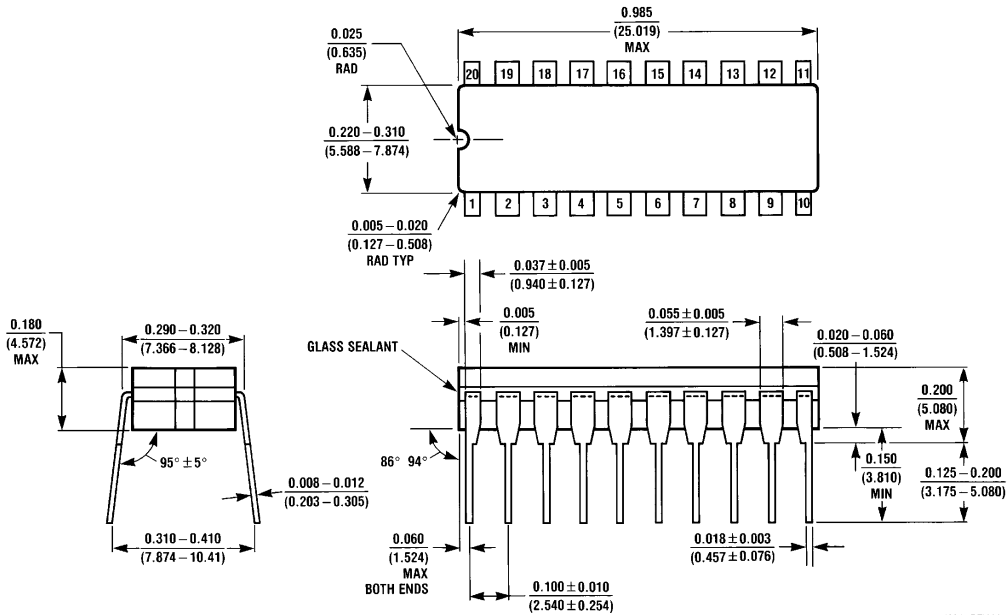


TL/H/5587-21



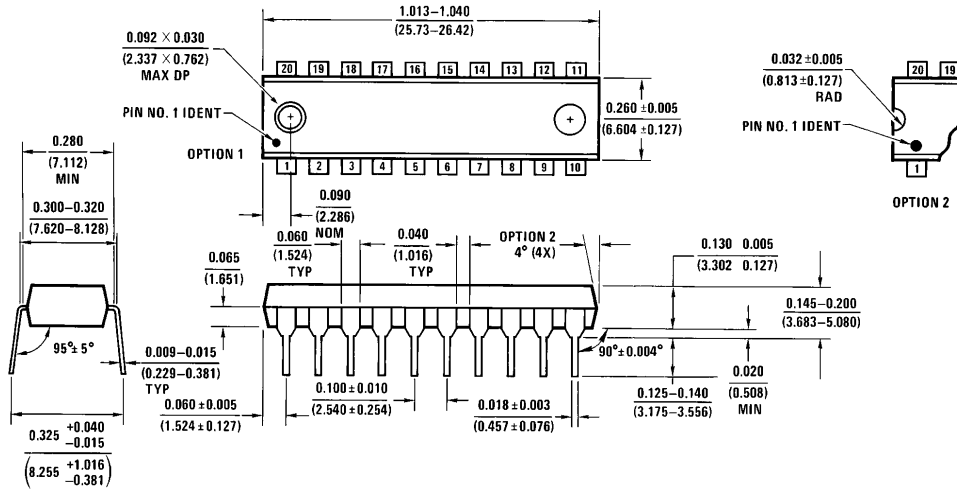


**Physical Dimensions** inches (millimeters)



J20A (REV M)

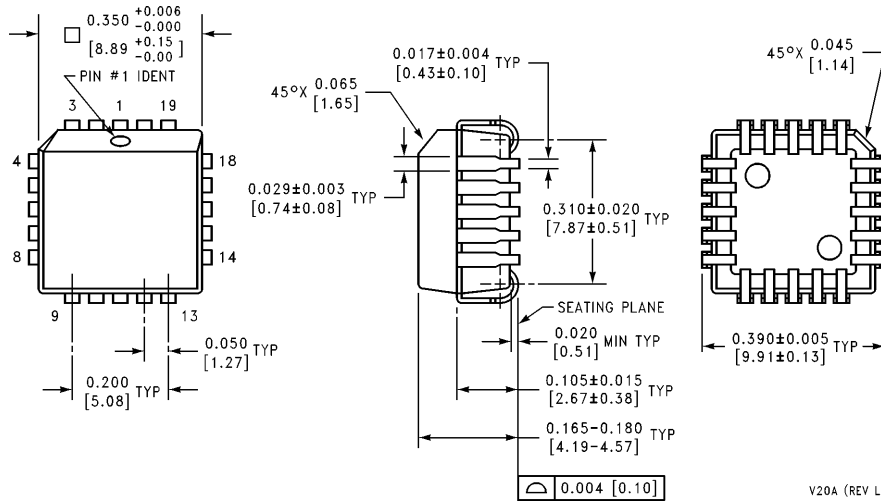
**Ceramic Dual-In-Line Package (J)**  
**Order Number ADC0811CCJ**  
**NS Package J20A**



N20A (REV G)

**Molded Dual-In-Line Package (N)**  
**Order Number ADC0811BCN, CCN**  
**NS Package N20A**

**Physical Dimensions** inches (millimeters) (Continued)



V20A (REV L)

**Molded Chip Carrier (V)**  
**Order Number ADC0811BCV, CCV**  
**NS Package V20A**

**LIFE SUPPORT POLICY**

NATIONAL'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF THE PRESIDENT OF NATIONAL SEMICONDUCTOR CORPORATION. As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and whose failure to perform, when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury to the user.
2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.



**National Semiconductor Corporation**  
 1111 West Bardin Road  
 Arlington, TX 76017  
 Tel: 1(800) 272-9959  
 Fax: 1(800) 737-7018

**National Semiconductor Europe**  
 Fax: (+49) 0-180-530 85 86  
 Email: cnjwge@tevm2.nsc.com  
 Deutsch Tel: (+49) 0-180-530 85 85  
 English Tel: (+49) 0-180-532 78 32  
 Français Tel: (+49) 0-180-532 93 58  
 Italiano Tel: (+49) 0-180-534 16 80

**National Semiconductor Hong Kong Ltd.**  
 19th Floor, Straight Block,  
 Ocean Centre, 5 Canton Rd.  
 Tsimshatsui, Kowloon  
 Hong Kong  
 Tel: (852) 2737-1600  
 Fax: (852) 2736-9960

**National Semiconductor Japan Ltd.**  
 Tel: 81-043-299-2309  
 Fax: 81-043-299-2408

National does not assume any responsibility for use of any circuitry described, no circuit patent licenses are implied and National reserves the right at any time without notice to change said circuitry and specifications.

This datasheet has been downloaded from:

[www.DatasheetCatalog.com](http://www.DatasheetCatalog.com)

Datasheets for electronic components.

# National Semiconductor was acquired by Texas Instruments.

[http://www.ti.com/corp/docs/investor\\_relations/pr\\_09\\_23\\_2011\\_national\\_semiconductor.html](http://www.ti.com/corp/docs/investor_relations/pr_09_23_2011_national_semiconductor.html)

This file is the datasheet for the following electronic components:

ADC0811CCJ - <http://www.ti.com/product/adc0811ccj?HQS=TI-null-null-dscatalog-df-pf-null-ww>

ADC0811BCN - <http://www.ti.com/product/adc0811bcn?HQS=TI-null-null-dscatalog-df-pf-null-ww>

ADC0811CCV - <http://www.ti.com/product/adc0811ccv?HQS=TI-null-null-dscatalog-df-pf-null-ww>

ADC0811CCN - <http://www.ti.com/product/adc0811ccn?HQS=TI-null-null-dscatalog-df-pf-null-ww>

ADC0811BCV - <http://www.ti.com/product/adc0811bcv?HQS=TI-null-null-dscatalog-df-pf-null-ww>



LittleDiode supplies new, hard to find or obsolete electronic components and semiconductors all over the world.

With over two million different components listed you are sure to find the part you need.

Feel free to visit us today at our online store:

[LittleDiode.com](http://LittleDiode.com)

Looking forward to providing you with the best possible service.